Extrapolation Technique Pitfalls in Asymmetry Measurements at Colliders

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Overview

- Background, Motivation, and Goals
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- Closed Form Statistical Validation
- Closed Form Numerical Validation
- Conclusions

Background, Motivation, and Goals

- It is common at colliders to measure asymmetries
 - e.g. Forward-Backward top quark pair production at the Tevatron
- Measurements in disagreement with SM NLO predictions are exciting – so we need to be confident in these measurements
- Often data is only measured in a visible region of the detector, Avisible
- This necessitates a method to measure the inclusive physical value, A^{inclusive}



 A simple yet powerful method often applicable is the use of a constant extrapolation factor

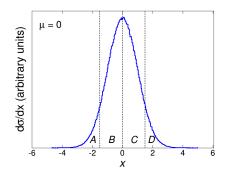
$$A^{\text{inclusive}} = R \cdot A^{\text{visible}}$$

Background, Motivation, and Goals

- Monte Carlo (MC) simulation (often a single pseudo-experiment) is typically used to estimate R
- So we want to understand two things through this study:
 - ullet whether we can confidently and reliably use a constant R to perform the extrapolation, and
 - ullet what the required MC sample size is to be able to reliably estimate R

Monte Carlo Study

- In this study we use a simple single Gaussian model 1 with a mean, μ $(\mu \propto A)$
- ullet A pseudo-experiment (PE) refers to generating a Gaussian distribution with a specified number of events, N



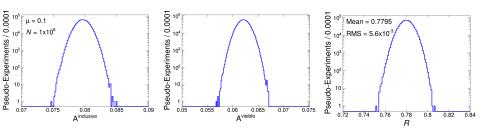
$$A^{inclusive} = \frac{(C+D) - (A+B)}{A+B+C+D}$$
$$A^{visible} = \frac{C-B}{B+C}$$

• $\mu=0.1$ corresponds to $A^{\rm inclusive} \approx 8\%$ which is typically seen in $A_{\rm FB}$ $t\bar{t}$ measurements

¹ Z. Hong, R. Edgar, S. Henry, D. Toback, J. S. Wilson, and D. Amidei, Phys. Rev. D 90 (2014) 014040.

Monte Carlo Study

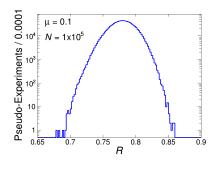
- Measure $A^{\text{inclusive}}$, A^{visible} , and R from a single PE
- With many PEs, we get distributions for $A^{\text{inclusive}}$, A^{visible} , and R:



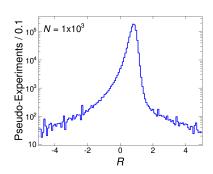
• What happens to the R distribution as we vary N and μ ?

Monte Carlo Study: Fix μ and Vary N

Fixed Value of μ with high statistics: Reliable measurement of R



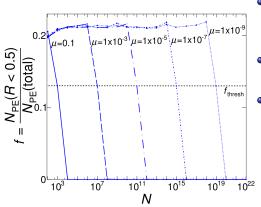
Fixed Value of μ with low statistics: Unreliable measurement of R



- With large enough sample size, measurements of R are very accurate
- As N decreases, measurement of R becomes <u>unreliable</u>, and can no longer correctly reproduce $A^{\text{inclusive}}$ from A^{visible}
- ullet This transition is observed for all values of μ

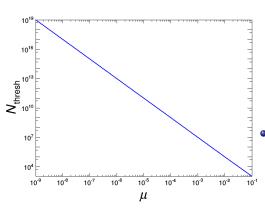
Monte Carlo Study: Quantifying the Transition for Varying μ

• We now examine how many events, $N_{\rm thresh}$, are needed to give reliable measurements of R



- We define f as the fraction of pseudo-experiments with R < 0.5
- This should be many σ from the mean, so we require $f \approx 0$
- To examine/quantify the behavior for reliable measurements, we define a threshold value, $f_{\rm thresh}$, and examine the relationship between $N_{\rm thresh}$ and μ

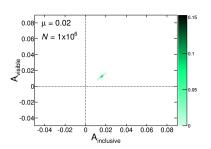
Monte Carlo Study: Results



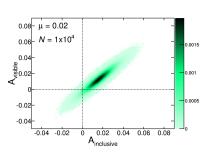
- We find that it can take a much-larger-than-expected sample size to reliably measure R, especially for very small μ (or equivalently A)
 - $N_{\rm thresh}$ rises as $\frac{1}{\mu^2}$ or $\frac{1}{A^2}$
- We also find that when N is large enough for reliable measurements, R is measured to be close to constant for all values of μ

Closed Form Statistical Validation: Number of Events Required for Reliable Measurements

"Enough" Events in Simulation – Reliable Measurements



"Not Enough" Events in Simulation –
Unreliable Measurements



• Require $A^{inclusive}$ (denominator of R) to be greater than at least 1σ away from 0

Closed Form Statistical Validation: Number of Events Required for Reliable Measurements

We can use statistics to answer the question of how many events,
 N_{thresh}, are required for this condition to be satisifed

$$A^{
m inclusive} \geq \sigma_{A_{FB}}{}_{
m inclusive}$$

• We are able to find N_{thresh} as a function of μ for our single Gaussian model (calculation in backup slides):

$$N_{\mathsf{thresh}} \geq 2 \cdot \frac{\left(1 + \mathsf{erf}\left(rac{\mu}{\sqrt{2}}
ight)
ight)}{\mathsf{erf}\left(rac{\mu}{\sqrt{2}}
ight)^2}$$

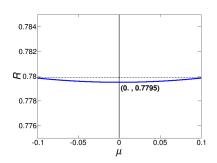
- Some limiting cases:
 - As $\mu o 0$, $N_{\mathsf{thresh}} o \infty$
 - erf $\left(\frac{\mu}{\sqrt{2}}\right) \approx \sqrt{\frac{2}{\pi}} \, \mu$ for small μ , so we find that $N_{\rm thresh} \propto \frac{1}{\mu^2}$ which is precisely what we just saw in the MC study

Closed Form Numerical Validation: Is R constant?

- Examining the behavior of R as a function of μ analytically is straightforward for the single Gaussian model
 - We set $\sigma = 1.0$ and use the visible region |x| < 1.5
- For large values of μ (i.e 0.1), R only rises by 0.04% relative to $R(\mu=0)$

Recall:

$$A^{inclusive} = rac{(C+D) - (A+B)}{A+B+C+D}$$
 $A^{visible} = rac{C-B}{B+C}$
 $R = rac{A^{visible}}{A^{inclusive}}$



Conclusions

- We have studied the multiplicative extrapolation of A^{visible} to $A^{\text{inclusive}}$ for the single Gaussian model, and while a custom study would be needed for any non-Gaussian physics distribution, we have observed that a linear extrapolation can be used in this and other similar cases
- While MC methods work reliably (even for small A), they can require much larger sample sizes than expected, rising as $\frac{1}{A^2}$
- ullet Our results have the potential to be applied to many different asymmetry measurements in collider experiments, and have already been useful at the Tevatron for the $tar{t}$ forward-backward asymmetry

Backups: The Cauchy Distribution

- A distribution of the ratio of two independent Gaussian variables
- Mean and RMS are undefined; though mode and median are well defined
- $A^{\text{inclusive}}$ and A^{visible} are approximately Gaussian, thus as the mean of the $A^{\text{inclusive}}$ distribution approaches 0, R begins approximating a Cauchy distribution

We need enough statistics such that $A_{FB}^{inclusive}$, the denominator of R, is more than 1 sigma away from 0 (we will set it to be k, where k will be determined later). In other words, we want to know how many events it takes in a pseudo-experiment to ensure the mean of the full asymmetry will be k standard-deviations away from zero.

To do this we start with the equation

$$\sigma_{A_{FB}^{inclusive}} = \frac{A_{FB}^{inclusive}}{k} \tag{1}$$

where $\sigma_{AFB}^{inclusive}$ is the variation (or uncertainty) of the measured value of $A_{FB}^{inclusive}$. We will find both $\sigma_{A_{FB}^{inclusive}}$ and $A_{FB}^{inclusive}$ as functions of N and μ and substitute them into Eq. 1 to get the functional relation between N and μ for "good statistics".

We begin with our definition of asymmetry,

$$A_{FB}^{inclusive} = \frac{N_{+} - N_{-}}{N_{+} + N_{-}} \tag{2}$$

where $N_+ = C + D$ and $N_- = A + B$ as on Slide 2. Next we define $N = N_+ + N_-$ as the total number of events in the original Gaussian distribution, and rewrite this as:

$$A_{FB}^{inclusive} = \frac{2N_{+} - N}{N}.$$
 (3)

We note that since our distributions are Gaussian, we can write N_+ in terms of N and μ , with the relation given by

$$N_{+} = \frac{N}{\sqrt{2\pi}} \int_{0}^{\infty} dx \ e^{-(x-\mu)^{2}/2}$$

$$= \frac{N}{2} \left(\operatorname{erf} \left(\frac{\mu}{\sqrt{2}} \right) + 1 \right)$$
(4)

Plugging this in to Eq. 3 and reducing, we get

$$A_{FB}^{inclusive} = \frac{2\frac{\mathcal{M}}{2}\left(\operatorname{erf}\left(\frac{\mu}{\sqrt{2}}\right) + 1\right) - \mathcal{M}}{\mathcal{M}}$$

$$= \operatorname{erf}\left(\frac{\mu}{\sqrt{2}}\right)$$
(5)

We next find $\sigma_{A_{FB}^{inclusive}}$ by beginning with the definition given in Bevington (92) applied to our problem,

$$\sigma_{A_{FB}^{inclusive}} = \left(\frac{\partial A_{FB}^{inclusive}}{\partial N_{+}}\right) \sigma_{N_{+}} + \left(\frac{\partial A_{FB}^{inclusive}}{\partial N}\right) \sigma_{N}. \tag{6}$$

Taking a simple derivative of $A_{FB}^{inclusive}$ from Eq. 3 gives us

$$\left(\frac{\partial A_{FB}^{inclusive}}{\partial N_{+}}\right) = \frac{2}{N} \tag{7}$$

To be consistent with the previous study, we fix N and allow N_+ to vary. This means that $\sigma_N=0$, and from simple statistics

$$\sigma_{N_{+}} = \sqrt{N_{+}} \tag{8}$$

Plugging Eqs. 7 and 8 into Eq. 6, we get

$$\sigma_{A_{FB}^{inclusive}} = \frac{2}{N} \cdot \sqrt{N_{+}}.$$
 (9)

Plugging Eq. 4 into this, we get

$$\sigma_{A_{FB}^{inclusive}} = \frac{2}{N} \cdot \sqrt{\frac{N}{2} \left(\text{erf} \left(\frac{\mu}{\sqrt{2}} \right) + 1 \right)}$$

$$= \sqrt{\frac{2}{N}} \cdot \sqrt{\left(1 + \text{erf} \left(\frac{\mu}{\sqrt{2}} \right) \right)}$$
(10)

Finally, plugging Eqs. 5 and 10 back into Eq. 1 gives us

$$\sqrt{\frac{2}{N}} \cdot \sqrt{\left(1 + \operatorname{erf}\left(\frac{\mu}{\sqrt{2}}\right)\right)} = \frac{\operatorname{erf}\left(\frac{\mu}{\sqrt{2}}\right)}{k}, \tag{11}$$

and solving for N, we get

$$N = \frac{2k^2 \left(1 + \operatorname{erf}\left(\frac{\mu}{\sqrt{2}}\right)\right)}{\operatorname{erf}\left(\frac{\mu}{\sqrt{2}}\right)^2}$$
(12)

This is, as we set out to solve for, the number of events it takes per pseudo-experiment to ensure the mean of the full asymmetry will be k standard-deviations away from zero, and thus give good statistics. Discussion of the implication of this result is included in the main slides.

Backups: Closed Form Numerical Solution Gaussian Functions

$$\begin{split} A_{FB}^{inclusive} &= \frac{\frac{1}{\sqrt{2\pi}\sigma} \int_0^\infty dx \big[\exp(-\frac{(x-\mu)^2}{2\sigma^2}) - \exp(-\frac{(-x-\mu)^2}{2\sigma^2}) \big]}{\frac{1}{\sqrt{2\pi}\sigma} \int_0^\infty dx \big[\exp(-\frac{(x-\mu)^2}{2\sigma^2}) + \exp(-\frac{(-x-\mu)^2}{2\sigma^2}) \big]} \\ A_{FB}^{visible} &= \frac{\frac{1}{\sqrt{2\pi}\sigma} \int_0^{1.5} dx \big[\exp(-\frac{(x-\mu)^2}{2\sigma^2}) - \exp(-\frac{(-x-\mu)^2}{2\sigma^2}) \big]}{\frac{1}{\sqrt{2\pi}\sigma} \int_0^{1.5} dx \big[\exp(-\frac{(x-\mu)^2}{2\sigma^2}) + \exp(-\frac{(-x-\mu)^2}{2\sigma^2}) \big]} \\ R &= \frac{A_{FB}^{visible}}{A^{inclusive}} \end{split}$$